Source	Error (%)			
	$(f_s/f_d)_{\rm sl}$	$(f_s/f_d)_{\rm h1}$	$(f_s/f_d)_{\rm h2}$	
Bin dependent error	1.0	-	-	Uncorrelated
Semileptonic decay modelling	3.0	-	-	Uncorrelated
Backgrounds	2.0	-	-	Uncorrelated
Fit model	-	2.8	2.8	Uncorrelated
Trigger simulation	-	2.0	2.0	Uncorrelated
Tracking efficiency	2.0	-	-	Uncorrelated
$\mathcal{B}(\overline{B}_s^0 \to D^0 K^+ X \mu^- \overline{\nu})$	$^{+4.1}_{-1.1}$	-	-	Uncorrelated
$\mathcal{B}(\overline{B}^0/B^- \to D_s^+ K X \mu^- \overline{\nu})$	2.0	-	-	Uncorrelated
Particle identification calibration	1.5	1.0	2.5	Correlated
B lifetimes	1.5	1.5	1.5	Correlated
$\mathcal{B}(D_s^+ \to K^+ K^- \pi^+)$	4.9	4.9	4.9	Correlated
$\mathcal{B}(D^+ \to K^- \pi^+ \pi^-)$	1.5	1.5	1.5	Correlated
SU(3) and form factors	-	6.1	6.1	Correlated
W-exchange	-	-	7.8	Uncorrelated